

# PATENT ABSTRACTS OF JAPAN

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## (54) STATIONARY PROBE BOARD

### (57)Abstract:

**PURPOSE:** To improve the reliability of test result by securing a stationary end to a mounting piece with conductivity, extending approximately axially of the mounting piece the end, and bending to face with the measuring electrode, thereby preventing the piezo effect.  
**CONSTITUTION:** Many probe needles 2' are radially arranged at the ends to be positioned at the electrodes of semiconductor chips to be measured at the position of a rectangular hole 9 formed at the center of a printed board 1. The other end of the mounting piece 10 of the needle is electrically connected via solder to the connecting end of the wiring pattern 6 of the substrate 1. The printed board 1 and the probe needle are integrally secured by the ring-shaped stationary unit 11 formed of insulating securing material so that the surface of the mounting piece becomes vertical to the mounting surface of the substrate 1.

